PSMN1R7-30YL

N-channel 30 V 1.7 m Ω logic level MOSFET in LFPAK

Rev. 04 — 20 April 2010

Product data sheet

1. Product profile

1.1 General description

Logic level N-channel MOSFET in LFPAK package qualified to 175 °C. This product is designed and qualified for use in a wide range of industrial, communications and domestic equipment.

1.2 Features and benefits

- Advanced TrenchMOS provides low RDSon and low gate charge
- High efficiency gains in switching power convertors
- Improved mechanical and thermal characteristics
- LFPAK provides maximum power density in a Power SO8 package

1.3 Applications

- DC-to-DC converters
- Lithium-ion battery protection
- Load switching

- Motor control
- Server power supplies

1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$		-	-	30	V
I _D	drain current	T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 1</u>	<u>[1]</u>	-	-	100	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	-	109	W
T _j	junction temperature			-55	-	175	°C
Static chara	acteristics						
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A};$ $T_j = 100 \text{ °C}; \text{ see } \frac{\text{Figure 16}}{\text{ or } 100 \text{ or } 1000 \text{ or } 100 \text{ or } 100 \text{ or } 100 \text{ or }$		-	-	2.4	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A};$ $T_j = 25 \text{ °C}$		-	1.29	1.7	mΩ
Dynamic characteristics							
Q_{GD}	gate-drain charge	$V_{GS} = 4.5 \text{ V}; I_D = 10 \text{ A};$ $V_{DS} = 12 \text{ V}; \text{ see } \frac{\text{Figure } 17}{\text{see } \frac{\text{Figure } 18}{\text{ V}}};$		-	8.7	-	nC



Table 1. Quick reference data ...continued

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
$Q_{G(tot)} \\$	total gate charge	$V_{GS} = 4.5 \text{ V}; I_D = 10 \text{ A};$ $V_{DS} = 12 \text{ V}; \text{ see } \frac{\text{Figure } 17}{}$		-	36.2	-	nC
Avalanche	ruggedness						
E _{DS(AL)R}	repetitive drain-source avalanche energy	see Figure 3	[2][3][4]	-	-	-	J

- [1] Continuous current is limited by package.
- [2] Single-pulse avalanche rating limited by maximum junction temperature of 175 °C.
- [3] Repetitive avalanche rating limited by average junction temperature of 170 °C.
- [4] Refer to application note AN10273 for further information.

2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		
2	S	source	mb	D
3	S	source		
4	G	gate	9	
mb	D	mounting base; connected to drain	1 2 3 4	mbb076 S
			SOT669 (LFPAK)	

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PSMN1R7-30YL	LFPAK	plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

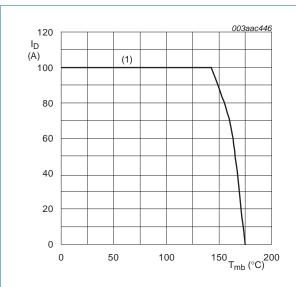
Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C		-	-	30	V
V_{DGR}	drain-gate voltage	$T_j \ge 25$ °C; $T_j \le 175$ °C; $R_{GS} = 20$ kΩ		-	-	30	V
V_{GS}	gate-source voltage			-20	-	20	V
I _D	drain current	$V_{GS} = 10 \text{ V}; T_{mb} = 100 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{\text{Model}}$	<u>[1]</u>	-	-	100	Α
		$V_{GS} = 10 \text{ V}; T_{mb} = 25 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{\text{Model}}$	<u>[1]</u>	-	-	100	Α
I _{DM}	peak drain current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$; see Figure 4		-	-	790	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	-	109	W
T _{stg}	storage temperature			-55	-	175	°C
Tj	junction temperature			-55	-	175	°C
Source-drain	diode						
I _S	source current	T _{mb} = 25 °C	[1]	-	-	100	Α
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$		-	-	790	Α
Avalanche rug	gedness						
E _{DS(AL)R}	repetitive drain-source avalanche energy	see Figure 3	[2][3][4]	-	-	-	J
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 100 A; $V_{sup} \le$ 30 V; R_{GS} = 50 Ω ; unclamped		-	-	241	mJ

^[1] Continuous current is limited by package.

^[2] Single-pulse avalanche rating limited by maximum junction temperature of 175 °C.

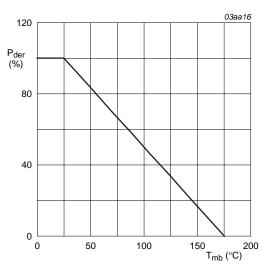
^[3] Repetitive avalanche rating limited by average junction temperature of 170 °C.

^[4] Refer to application note AN10273 for further information.



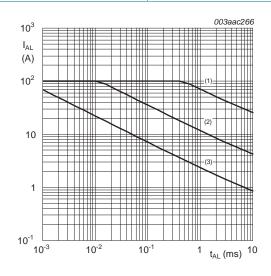
 $V_{GS} \ge 10 \ V$; (1) Capped at 100 A due to package

Fig 1. Continuous drain current as a function of mounting base temperature



$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$

Fig 2. Normalized total power dissipation as a function of mounting base temperature

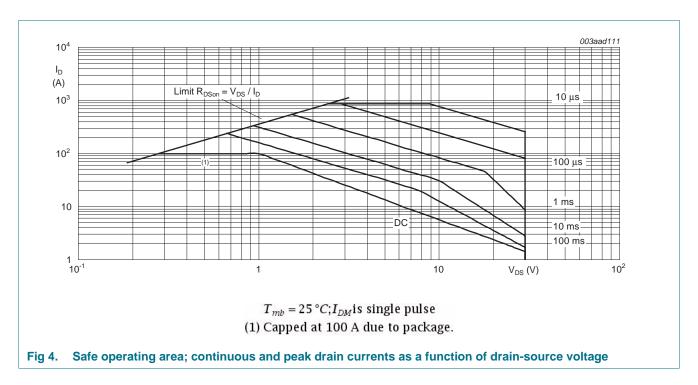


(1) Single-pulse; $T_j = 25 \,^{\circ}C$.

(2) Single-pulse; $T_j = 150 \,^{\circ}C$.

(3) Repetitive.

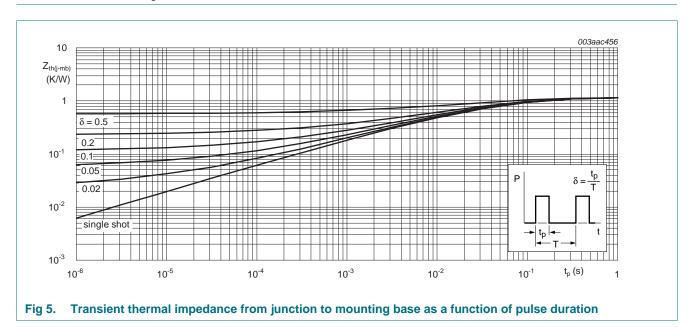
Fig 3. Single-pulse and repetitive avalanche rating; avalanche current as a function of avalanche time



5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 5	-	0.5	1.1	K/W



6. Characteristics

Table 6. Characteristics

Tested to JEDEC standards where applicable.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static chara	cteristics					
$V_{(BR)DSS}$	drain-source breakdown voltage	I_D = 20 A; V_{GS} = 0 V; T_j = 25 °C; t_{av} = 100 ns	35	-	-	V
		$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 °C$	30	-	-	V
		$I_D = 250 \mu A; V_{GS} = 0 V; T_j = -55 °C$	27	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	I_D = 1 mA; V_{DS} = V_{GS} ; T_j = 25 °C; see <u>Figure 14</u> ; see <u>Figure 15</u>	1.3	1.7	2.15	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 150$ °C; see <u>Figure 15</u>	0.65	-	-	V
		I_D = 1 mA; V_{DS} = V_{GS} ; T_j = -55 °C; see <u>Figure 15</u>	-	-	2.45	V
I _{DSS}	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	1	μΑ
		$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 \text{ °C}$	-	-	100	μΑ
I _{GSS}	gate leakage current	$V_{GS} = 16 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	100	nA
		$V_{GS} = -16 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	100	nA
R _{DSon}	drain-source on-state resistance	$V_{GS} = 4.5 \text{ V}; I_D = 15 \text{ A}; T_j = 25 \text{ °C}$	-	1.75	2.09	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 150 \text{ °C};$ see Figure 16	-	-	2.8	mΩ
		$V_{GS} = 10 \text{ V; } I_D = 15 \text{ A; } T_j = 100 \text{ °C;}$ see <u>Figure 16</u>	-	-	2.4	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 25 \text{ °C}$	-	1.29	1.7	mΩ
R_G	gate resistance	f = 1 MHz	-	0.77	1.5	Ω
Dynamic ch	aracteristics					
$Q_{G(tot)}$	total gate charge	$I_D = 10 \text{ A}$; $V_{DS} = 12 \text{ V}$; $V_{GS} = 10 \text{ V}$; see Figure 17; see Figure 18	-	77.9	-	nC
		$I_D = 0 \text{ A}; V_{DS} = 0 \text{ V}; V_{GS} = 10 \text{ V}$	-	70	-	nC
		$I_D = 10 \text{ A}$; $V_{DS} = 12 \text{ V}$; $V_{GS} = 4.5 \text{ V}$; see Figure 17	-	36.2	-	nC
Q_{GS}	gate-source charge	$I_D = 10 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$	-	11.6	-	nC
Q _{GS(th)}	pre-threshold gate-source charge	see <u>Figure 17</u> ; see <u>Figure 18</u>	-	8	-	nC
Q _{GS(th-pl)}	post-threshold gate-source charge		-	3.6	-	nC
Q_{GD}	gate-drain charge		-	8.7	-	nC
V _{GS(pI)}	gate-source plateau voltage	V _{DS} = 12 V; see <u>Figure 17</u> ; see <u>Figure 18</u>	-	2.34	-	V
C _{iss}	input capacitance	V _{DS} = 12 V; V _{GS} = 0 V; f = 1 MHz;	-	5057	-	pF
C _{oss}	output capacitance	T _j = 25 °C; see <u>Figure 19</u>	-	1082	-	pF
C _{rss}	reverse transfer capacitance		-	398	-	pF

 Table 6.
 Characteristics ...continued

Tested to JEDEC standards where applicable.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
t _{d(on)}	turn-on delay time	$V_{DS} = 12 \text{ V}; R_L = 0.5 \Omega; V_{GS} = 4.5 \text{ V};$	-	46	-	ns
t _r	rise time	$R_{G(ext)} = 4.7 \Omega$	-	72	-	ns
t _{d(off)}	turn-off delay time		-	76	-	ns
t _f	fall time		-	34	-	ns
Source-dra	in diode					
V_{SD}	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C};$ see <u>Figure 20</u>	-	0.78	1.2	V
t _{rr}	reverse recovery time	$I_S = 20 \text{ A}$; $dI_S/dt = -100 \text{ A/}\mu\text{s}$; $V_{GS} = 0 \text{ V}$;	-	45	-	ns
Q _r	recovered charge	V _{DS} = 20 V	-	56	-	nC

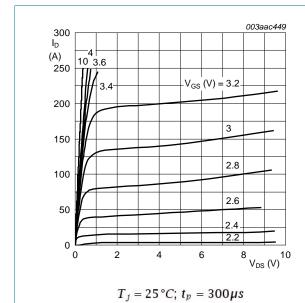


Fig 6. Output characteristics: drain current as a function of drain-source voltage; typical values

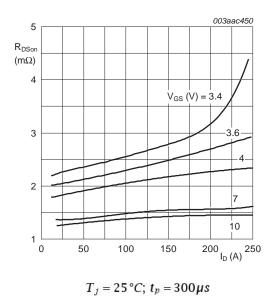


Fig 7. Drain-source on-state resistance as a function of drain current; typical values

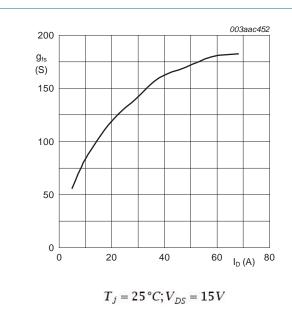


Fig 8. Forward transconductance as a function of drain current; typical values

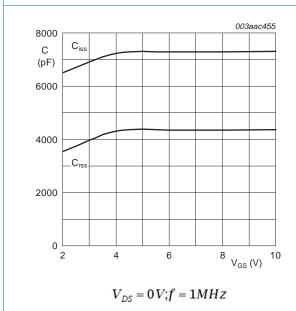


Fig 10. Input and reverse transfer capacitances as a function of gate-source voltage; typical values

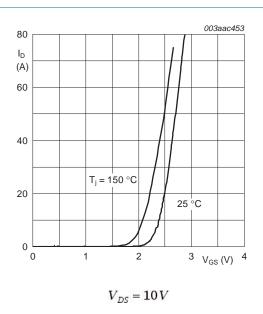
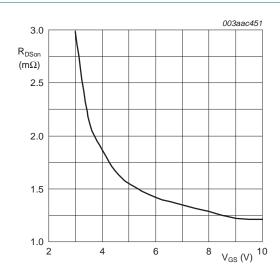
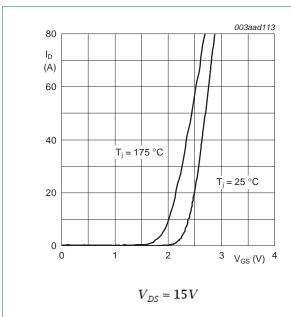


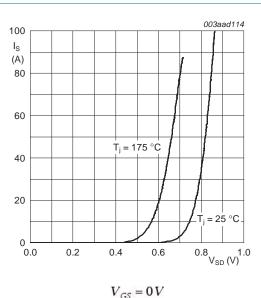
Fig 9. Transfer characteristics: drain current as a function of gate-source voltage; typical values



 $T_j=25\,^{\circ}C; I_D=15A$

Fig 11. Drain-source on-state resistance as a function of gate-source voltage; typical values

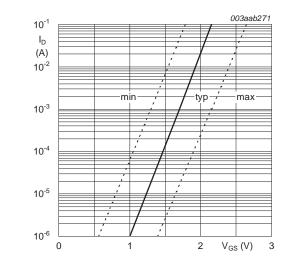




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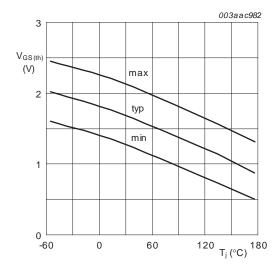






 $T_j = 25\,^{\circ}C; V_{DS} = 5\,V$

Fig 14. Sub-threshold drain current as a function of gate-source voltage



 $I_D = 1mA; V_{DS} = V_{GS}$

Fig 15. Gate-source threshold voltage as a function of junction temperature

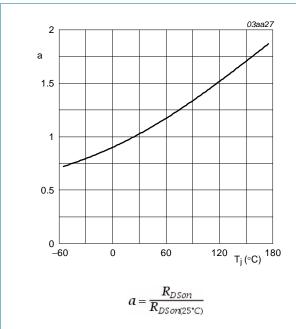


Fig 16. Normalized drain-source on-state resistance factor as a function of junction temperature

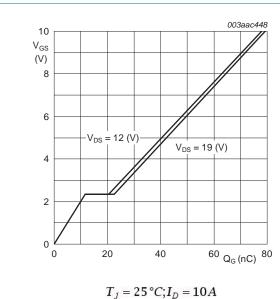


Fig 18. Gate-source voltage as a function of gate charge; typical values

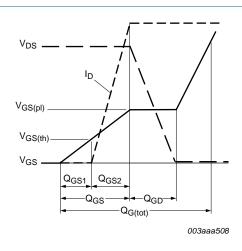
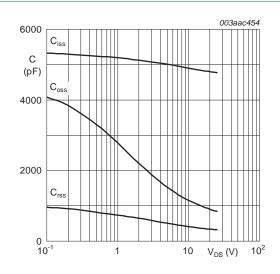


Fig 17. Gate charge waveform definitions



 $V_{GS} = 0V; f = 1MHz$

Fig 19. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

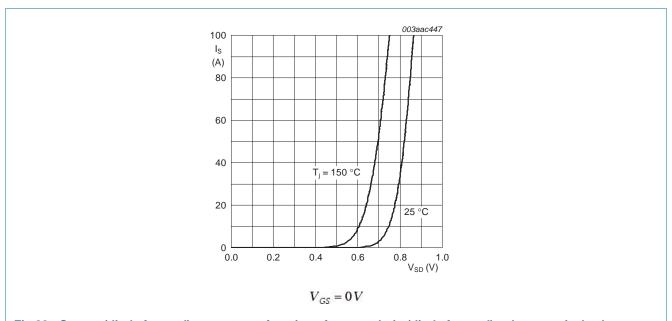


Fig 20. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values

7. Package outline

Plastic single-ended surface-mounted package (LFPAK); 4 leads

SOT669

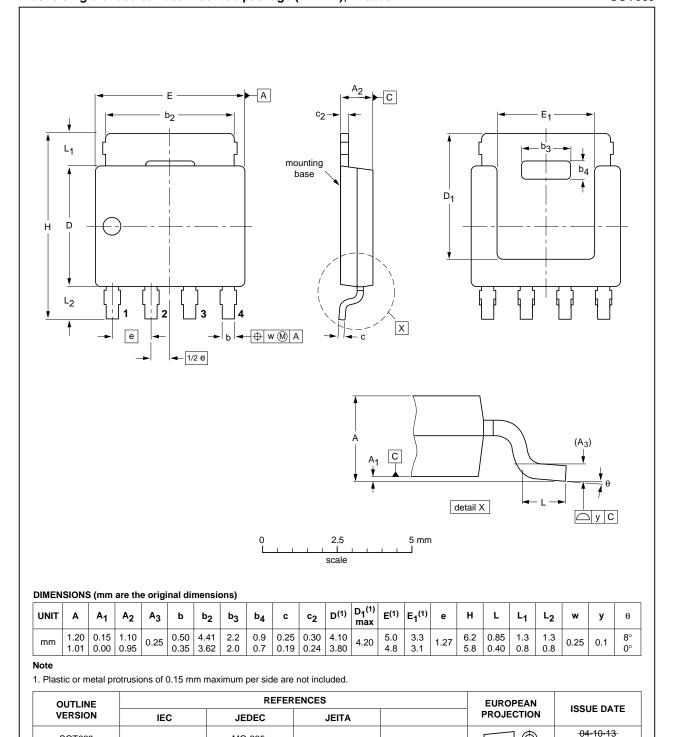


Fig 21. Package outline SOT669 (LFPAK)

PSMN1R7-30YL

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06-03-16

SOT669

8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
PSMN1R7-30YL_4	20100420	Product data sheet	-	PSMN1R7-30YL_3
Modifications:	 Various cha 	anges to content.		
PSMN1R7-30YL_3	20100111	Product data sheet	-	PSMN1R7-30YL_2

9. Legal information

9.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
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N-channel 30 V 1.7 m Ω logic level MOSFET in LFPAK

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PSMN1R7-30YL

NXP Semiconductors

N-channel 30 V 1.7 m Ω logic level MOSFET in LFPAK

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